Hybrid 8j122 Traveler

January 4, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J122 has die: 097-036 097-038 097-040 097-041 197-092 197-095 197-096 197-097

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j122 classification info. Created 12:28:17 12/06/99

Hybrid 8j122 quality: bad
Chip classification: bad good fair good good fair good good
Bad channels (chip-channel): 0-0 0-1 0-2 0-4 5-87
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-28-0 5-11-87 5-17-87
   5-19-87 5-20-87 5-23-87 5-24-87 5-29-87 5-33-87
Channels at pedestal needed for DCMS: 30.7 34.6 36.6 34.6 31.7 32.7 33.6 32.6
```

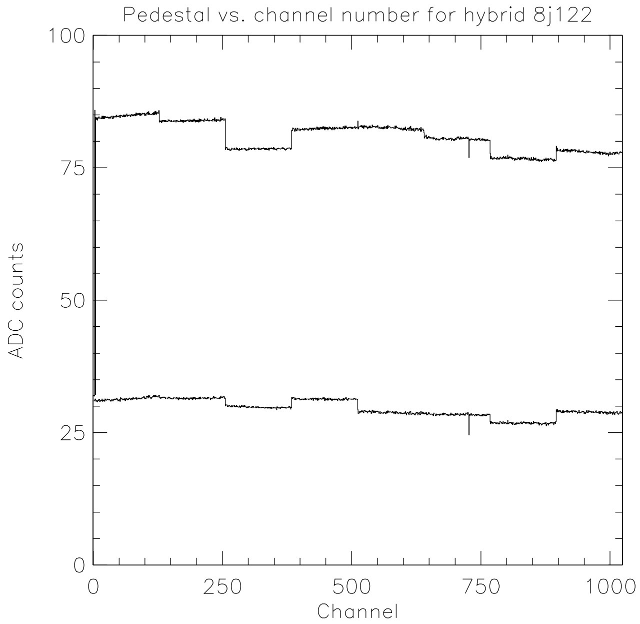
4 Comments

No comments.

5 Pedestal

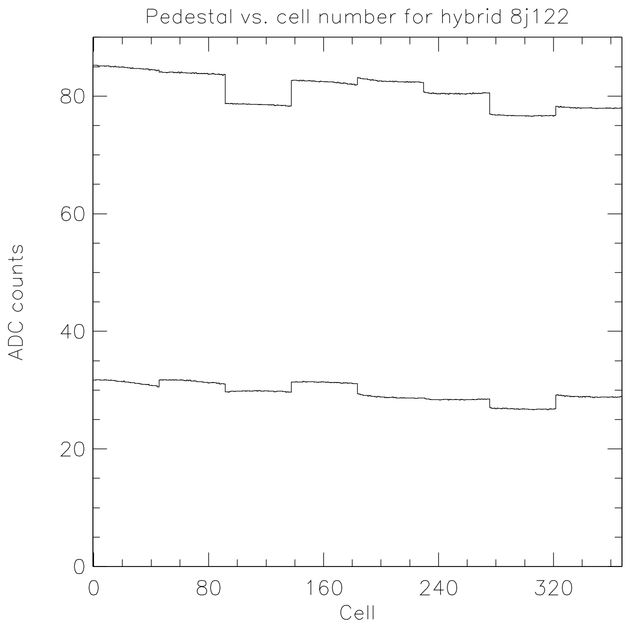
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

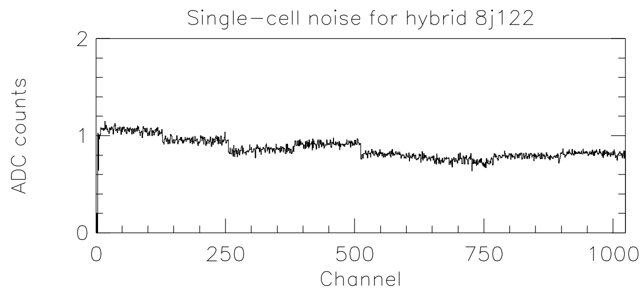
Pedestal vs. Pipeline Cell ID

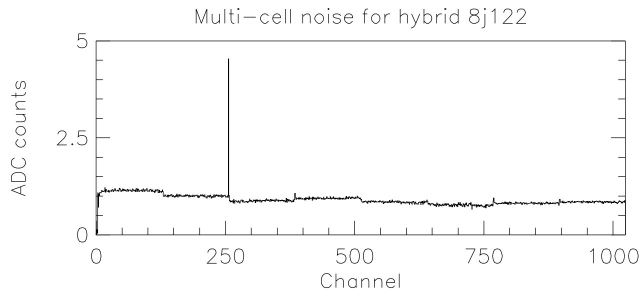


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

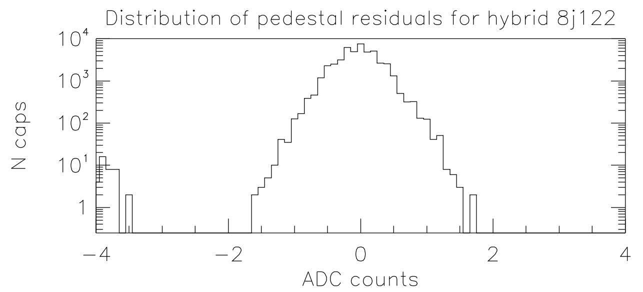
RMS Noise

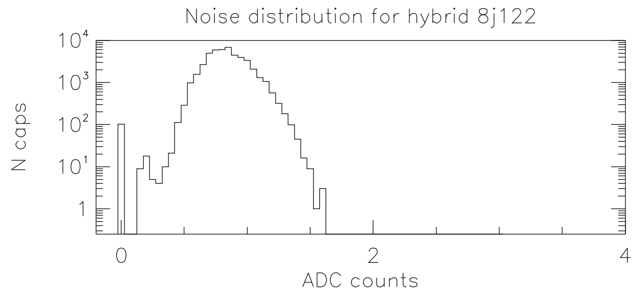




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in